

EIGER2 R 500K for the D8 Family

Jon Giенcke, Brian Jones, Nathan Henderson, S. Nick Rodesney
Bruker AXS – 5465 East Cheryl Pkwy – Madison, WI - US

The D8 family of X-ray diffractometers, including the D8 ADVANCE and D8 DISCOVER, combine exceptional ease of use with ultimate versatility. Fundamental modularity and a continuous stream of innovative components, such as dynamic beam optimization and the multi-beam path TRIO primary optic, ensure the latest technology is always available for the D8 platform. The EIGER2 R 500K from DECTRIS, well known for industry leading beamline detector technology, represents the latest innovation to be integrated into the D8 family.

The EIGER2 R 500K for the D8 family combines the newest generation of Hybrid Photon Counting (HPC) pixel detector technology with comprehensive solution level integration including 0D, 1D and 2D snapshot, basic scanning and advanced scanning modes using proprietary methods which ensure the highest quality data in the minimum collection time. DIFFRAC.SUITE provides a seamless user experience from measurement planning to data analysis when using the EIGER2 R 500K in 0D, 1D and 2D mode.

In this presentation examples will be provided of samples ranging from geological specimens, bulk metals and epitaxial thin films with applications ranging from enhanced phase identification, native 2D texture and large area reciprocal space mapping.

